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Abstract
With the rapid development on the technology of TFT-LCD these years, the quality improvement of products is increasingly demanded. Basically, various inspection about brightness including uniformity, gray scale, gamma…etc, are carried out before shipment. However the transient analysis on the variation of brightness during the long term thermal aging (LTTA) process is ignored. Because the quality is always inspected by human eyes instead of machine. Besides, the aging machine does not provide the functionality of monitoring the color or brightness transient. Thus the failure mechanism can not be captured and feedback to improve the process for yield.
In this paper, we propose a brightness quality tracing system for TFT-LCD testing. A test pattern generator based on uC+CPLD is developed to generate specific test patterns. The luminance, voltage, and current data are sampled with respect to the test patterns. These real time data are stored and sent to a PC for further analysis. Either the operators or reliability analysis engineers can inspect the quality from the waveform on the GUI or database respectively.
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